

**Search Notes**

Application/Control No.

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Examiner

Wen-Ying P. Chen

Applicant(s)/Patent under  
Reexamination

NIIYA, HIROTAKE

Art Unit

2871

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Reviewed previously cited references	11/17/2005	WPC
Citations search of tagged references	11/17/2005	WPC